

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: **Cann et al.**  
Serial No.: **10/711,765**  
Filed: **October 4, 2004**  
For: **Inspection Methods and Structures for Visualizing and/or Detecting Specific Chip Structures**  
Dkt. No.: **BUR920040035US1**  
Conf. No.: **5764**  
Examiner: **Lee, H.**  
Art Unit: **2823**

OK

to  
enter  
Lee  
2/9/07

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**After-Final Amendment**

Sir:

**Introductory Comments**

In response to the Final Office Action dated January 22, 2007, Applicants respond as follows:

10/711,765